Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/615,554	DOBISZ ET AL.	
Examiner	Art Unit	
Tianjie Chen	2652	

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Class	Subclass	Date	Examiner
360	324.12		
	324.2		
	327.3		
	327.32	10/17/2005	TJ

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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